



PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1427		SERIAL NO. 09/559,903		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.				
				FILING DATE April 26, 2000		GROUP 2815		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
AW	AA	US 2001/0003064 A1	06-2001	Ohto			Dec. 4, 2000	
AW	AB	US 2003/0013311 A1	01-2003	Chang et al.			Jul. 3, 2001	
	AC							
	AD							
	AE							
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclasses	Translation	
							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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	AS							
EXAMINER				/Allan Wilson/				
				DATE CONSIDERED 05/03/2006				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

EL46567 0034 09/559903

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET
M123-1477SERIAL NO.
E123456789LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed Horvath 4/26/00

GROUP 2815

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
JK	AA 4,954,857	09/04/90	Hosaka	257	639	
JK	AB 5,441,797	08/15/95	Hagan et al.	428	209	
JK	AC 5,472,827	12/05/95	Ogawa et al.	430	315	
JK	AD 5,674,356	10/07/97	Nagayama	438	694	
JK	AE 5,710,067	01/20/98	Foster et al.	438	636	
JK	AF 5,731,242	03/24/98	Parat et al.	438	566	
JK	AG 5,741,721	04/21/98	Sorensen	439	396	
JK	AH 5,759,755	06/02/98	Park et al.	430	512	
JK	AI 5,838,052	11/17/98	McTeer	257	437	
	AK					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
JK	AL JP06067019A	1/14/91	Japan (Abstract)	-	-		
JK	AM 0 471 185 A2	2/14/92	EPO	-	-		
JK	AN 0 588 087 A2	3/24/94	EPO	-	-		
JK	AO 0 588 087 A3	3/24/94	EPO	-	-		
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

JK	AR	ARTICLE: Bencher, C. et al., "Dielectric antireflective coatings for DUV lithography", Solid State Technology (March 1997), pp. 109-114.
JK	AS	ARTICLE: Dammet, R. R. et al., "Dependence of Optical Constants of AZ® BARLI™ Bottom Coating on Back Conditions", SPIE Vol. 3049 (1997), pp. 963-973.
JK	AT	TEXT: Heavens, O. S., "Optical Properties of Thin Solid Films", pp. 48-49.

EXAMINER

JK E. H. A. =

DATE CONSIDERED

2/28/01

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		FILING DATE Filed Herein 4/26/00	
				GROUP		2815	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
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		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
9/22	AR			TEXT: Jenkins, P. et al., "Fundamentals of Optics", Properties of Light, pp. 9-10.			
9/22	AS			TEXT: Wolf, S. et al., "Silicon Processing for the VLSI Era", Vol. 1, pp. 437-441.			
	AT						
EXAMINER		9/22 E. H. T.		DATE CONSIDERED 9/28/01			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. 08/559,903	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.		FILING DATE April 26, 2000	
				GROUP 2816			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
gk	AA	5,472,829	12/95	Ogawa	430	325	
gk	AB	5,591,566	01/97	Ogawa	430	325	
gk	AC	5,641,607	06/97	Ogawa et al.	430	272.15	
gk	AD	5,648,202	07/97	Ogawa et al.	430	325	
gk	AE	5,677,111	10/97	Ogawa	430	313	
gk	AF	5,670,297	09/97	Ogawa et al.	430	318	
gk	AG	5,698,352	12/97	Ogawa et al.	430	14	
gk	AH	5,831,321	11/98	Nagayama	257	412	
gk	AI	5,034,348	07/91	Hartswick et al.	438	453	
gk	AJ	6,008,124	12/99	Schiguchi et al.	438	653	
gk	AK	5,340,621	08/94	Matsumoto et al.	427	571	
gk	AL	5,600,165	02/97	Tinkamotto et al.	257	323	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
gk	AM	0-778496 A2/A3	06/97	EPO	-	-	-
gk	AN	9-55351	02/97	Japan	-	-	-
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
gk	AR			McKenzie, D. et al., "New Technology for PACVD", Surface and Coatings Technology 82 (1996), pp. 326-333.			
gk	AS			Sakuma, Noboru, "Plasma-Chemical Vapor-Deposited Silicon Oxide/Silicon Oxynitride Double-Layer Antireflective Coating for Solar Cells", Jap. Journ. of Applied Physics, Vol. 30, No. 5, May 1991, pp. 997-1001.			
	AT						
EXAMINER				DATE CONSIDERED			
gk				9/20/01			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-1427		SERIAL NO. 69/559,903		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.		GROUP 2815		
				FILING DATE April 26, 2000				
U.S. PATENT DOCUMENTS								
*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
jm	AA	5,964,324	10/99	Cheung et al.	204	192.28		
jm	AB	5,872,345	02/99	Taft et al.	257	437		
jm	AC	5,883,011	04/99	Lia et al.	438	747		
jm	AD	5,960,289	09/99	Tsui et al.	438	275		
jm	AE	6,020,243	02/00	Wallace et al.	438	287		
	AF							
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	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
jm	AM	US 99/20029	08/99	PCT Search Report				
jm	AN	US 99/20030	08/99	PCT Search Report				
	AO							
	AP							
	AO							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER <i>gsc Eckert</i>				DATE CONSIDERED <i>9/28/01</i>				

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. 09/559,903		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yia et al.		GROUP 2815		
				FILING DATE April 26, 2000				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
gze	AA	App. 09/030,618 as filed and amended	2/25/98	Hotscher			02/98	
	AB							
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	AD							
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	FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER		gze Ebert			DATE CONSIDERED			
					9/20/01			
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Form PTO-1419		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 2003-1437		SERIAL NO. 09-277,003	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhang, Y. et al.			
				FILING DATE April 24, 2003		GROUP 2813	
U.S. PATENT DOCUMENTS							
Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Applicable
YK	AA	6,133,418	10-2000	Enrich			
	AB	5,984,317	11-1999	Ng			
	AC	5,933,309	11-1999	Kabane et al.			
	AD	5,147,388	05-1998	KUMPTI et al.			
	AE	5,639,687	06-1997	Roman et al.			
	AF	5,498,333	03-1996	Lin			
	AG						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AM						
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	AO						
	AP						
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
YK	A R	Watt, S. "Silicon Processing for the VLSI Era," Vol. 1, pp. 407-413.					
YK	AE	Watt, S. "Silicon Processing for the VLSI Era," Vol. 1, pp. 40-49 and 411.					
EXAMINER				DATE CONSIDERED			
YK/mo				2/17/04			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with oral communication to applicant.</small>							

F.T. 979950463

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M23-147		SERIAL NO. 09719,900	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhang Yin et al.			
				FILING DATE April 24, 2003		GROUP 2815	
U.S. PATENT DOCUMENTS							
Number Tablet		Document Number	Date	Name	Class	Subclass	Filing Date if Applicable
96	AA	US 2001/003061 A1	06-2001	Chen			Dec. 4, 2000
97	AB	US 2001/001311 A1	01-2001	Cheng et al.			Jul. 3, 2001
	AC						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER		9X5h*		DATE CONSIDERED 2/17/04			
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